



Attorney Docket No. 5649-1276

IRW
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re: Young-pil Kim et al.

Examiner: Matthew C. Landau

Serial No.: 10/796,672

Group Art Unit: 2815

Filed: March 9, 2004

Confirmation No.: 3015

For: **Semiconductor Device Test Patterns and Related Methods for Precisely
Measuring Leakage Currents in Semiconductor Cell Transistors**

Date: April 7, 2006

Mail Stop AMENDMENT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE TO NOTICE OF NON-COMPLIANT AMENDMENT

Sir:

In response to the Notice of Non-Compliant Amendment ("the Notice") dated March 30, 2006, Applicants provide the present Amendment to supplement the Amendment filed January 6, 2006. Pursuant to the instructions in the Notice, only the entire corrected claim amendment section of the non-compliant amendment document is provided below.